

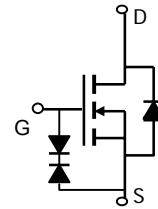
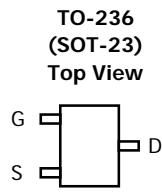


**ALPHA & OMEGA**  
SEMICONDUCTOR LTD.

Rev 2: Nov 2004

## AO3416, AO3416L ( Green Product ) N-Channel Enhancement Mode Field Effect Transistor

General Description	Features
<p>The AO3416 uses advanced trench technology to provide excellent <math>R_{DS(ON)}</math>, low gate charge and operation with gate voltages as low as 1.8V. This device is suitable for use as a load switch or in PWM applications. It is ESD protected. AO3416L ( Green Product ) is offered in a lead-free package.</p>	<p><math>V_{DS}</math> (V) = 20V  <math>I_D</math> = 6.5 A  <math>R_{DS(ON)} &lt; 22m\Omega</math> (<math>V_{GS} = 4.5V</math>)  <math>R_{DS(ON)} &lt; 26m\Omega</math> (<math>V_{GS} = 2.5V</math>)  <math>R_{DS(ON)} &lt; 34m\Omega</math> (<math>V_{GS} = 1.8V</math>)  ESD Rating: 2000V HBM</p>



Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted				
Parameter	Symbol	Maximum	Units	
Drain-Source Voltage	$V_{DS}$	20	V	
Gate-Source Voltage	$V_{GS}$	$\pm 8$	V	
Continuous Drain Current <sup>A</sup>	$T_A=25^\circ C$	6.5	A	
$T_A=70^\circ C$		5.2		
Pulsed Drain Current <sup>B</sup>	$I_{DM}$	30		
Power Dissipation <sup>A</sup>	$T_A=25^\circ C$	1.4	W	
		0.9		
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to 150	°C	

Thermal Characteristics				
Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient <sup>A</sup>	$t \leq 10s$	65	90	°C/W
Maximum Junction-to-Ambient <sup>A</sup>		85	125	°C/W
Maximum Junction-to-Lead <sup>C</sup>	Steady-State	43	60	°C/W

**Electrical Characteristics ( $T_J=25^\circ\text{C}$  unless otherwise noted)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}, V_{GS}=0\text{V}$	20			V
$I_{\text{DSS}}$	Zero Gate Voltage Drain Current	$V_{DS}=16\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$			1	$\mu\text{A}$
					5	
$I_{\text{GSS}}$	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm 4.5\text{V}$			$\pm 1$	$\mu\text{A}$
		$V_{DS}=0\text{V}, V_{GS}=\pm 8\text{V}$			$\pm 10$	$\mu\text{A}$
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	0.4	0.6	1	V
$I_{D(\text{ON})}$	On state drain current	$V_{GS}=4.5\text{V}, V_{DS}=5\text{V}$	30			A
$R_{DS(\text{ON})}$	Static Drain-Source On-Resistance	$V_{GS}=4.5\text{V}, I_D=6.5\text{A}$ $T_J=125^\circ\text{C}$		18	22	$\text{m}\Omega$
		$V_{GS}=2.5\text{V}, I_D=5.5\text{A}$		25	30	
		$V_{GS}=1.8\text{V}, I_D=5\text{A}$		21	26	
$g_{FS}$	Forward Transconductance	$V_{DS}=5\text{V}, I_D=6.5\text{A}$		26	34	$\text{m}\Omega$
$V_{SD}$	Diode Forward Voltage	$I_S=1\text{A}, V_{GS}=0\text{V}$		0.76	1	V
$I_S$	Maximum Body-Diode Continuous Current				2.5	A
<b>DYNAMIC PARAMETERS</b>						
$C_{iss}$	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=10\text{V}, f=1\text{MHz}$		1160		$\text{pF}$
$C_{oss}$	Output Capacitance			187		$\text{pF}$
$C_{rss}$	Reverse Transfer Capacitance			146		$\text{pF}$
$R_g$	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$		1.5		$\Omega$
<b>SWITCHING PARAMETERS</b>						
$Q_g$	Total Gate Charge	$V_{GS}=4.5\text{V}, V_{DS}=10\text{V}, I_D=6.5\text{A}$		16		$\text{nC}$
$Q_{gs}$	Gate Source Charge			0.8		$\text{nC}$
$Q_{gd}$	Gate Drain Charge			3.8		$\text{nC}$
$t_{D(\text{on})}$	Turn-On DelayTime	$V_{GS}=5\text{V}, V_{DS}=10\text{V}, R_L=1.5\Omega, R_{\text{GEN}}=3\Omega$		6.2		ns
$t_r$	Turn-On Rise Time			12.7		ns
$t_{D(\text{off})}$	Turn-Off DelayTime			51.7		ns
$t_f$	Turn-Off Fall Time			16		ns
$t_{rr}$	Body Diode Reverse Recovery Time	$I_F=6.5\text{A}, dI/dt=100\text{A}/\mu\text{s}$		17.7		ns
$Q_{rr}$	Body Diode Reverse Recovery Charge	$I_F=6.5\text{A}, dI/dt=100\text{A}/\mu\text{s}$		6.7		$\text{nC}$

A: The value of  $R_{\theta JA}$  is measured with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The value in any given application depends on the user's specific board design. The current rating is based on the  $t \leq 10\text{s}$  thermal resistance rating.

B: Repetitive rating, pulse width limited by junction temperature.

C. The  $R_{\theta JA}$  is the sum of the thermal impedance from junction to lead  $R_{\theta JL}$  and lead to ambient.

D. The static characteristics in Figures 1 to 6,12,14 are obtained using 80  $\mu\text{s}$  pulses, duty cycle 0.5% max.

E. These tests are performed with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The SOA curve provides a single pulse rating.

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## TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

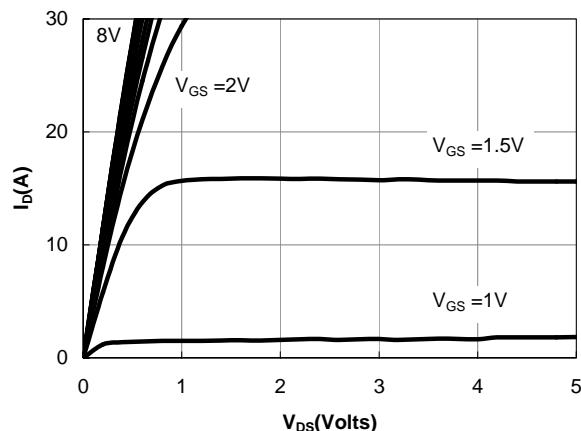


Figure 1: On-Regions Characteristics

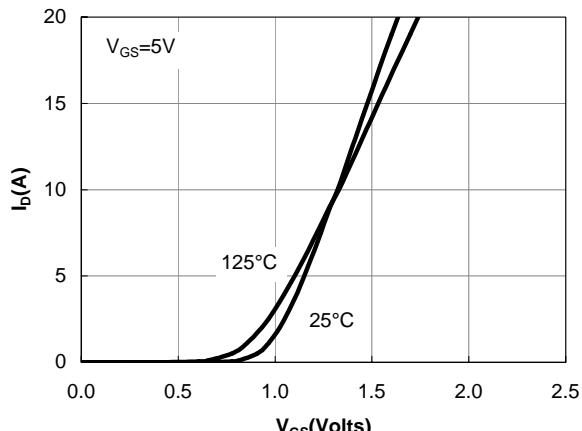


Figure 2: Transfer Characteristics

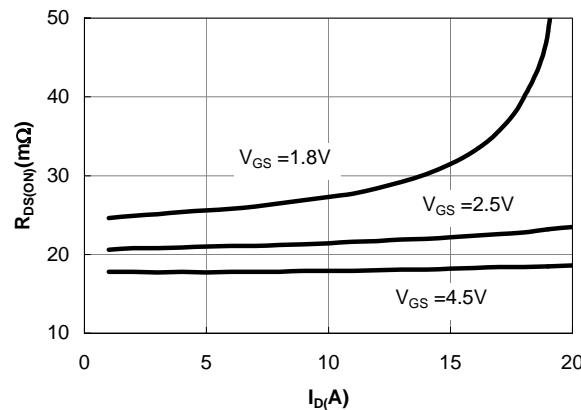


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

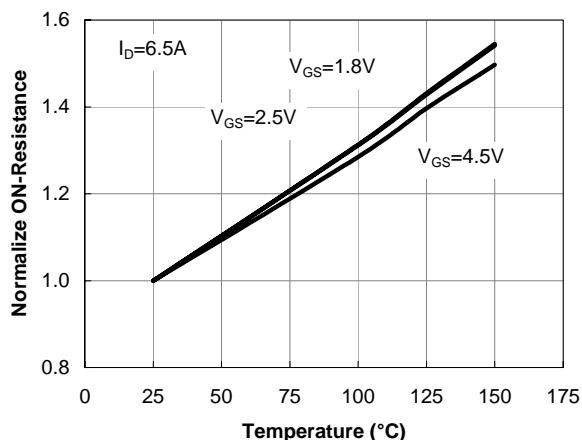


Figure 4: On-Resistance vs. Junction Temperature

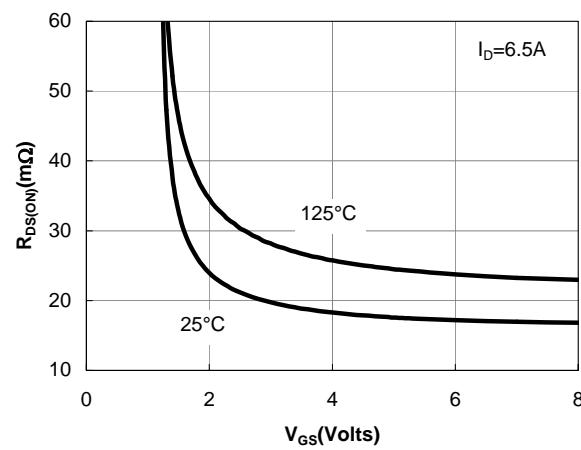


Figure 5: On-Resistance vs. Gate-Source Voltage

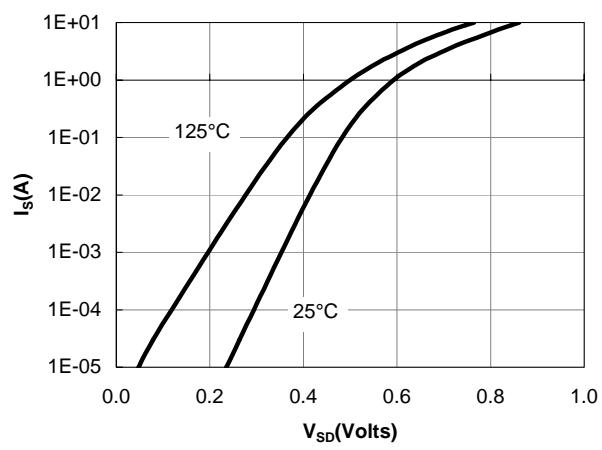


Figure 6: Body-Diode Characteristics

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